

Notice of References Cited	Application/Control No. 10/743,834	Applicant(s)/Patent Under Reexamination SAKAI ET AL.	
	Examiner JYOTHSNA A. VENKAT Ph. D	Art Unit 1615	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,034,218	07-1991	Duvel, Lane A.	424/70.12
*	B	US-5,977,038	11-1999	Birtwistle et al.	510/122
*	C	US-2005/0095217	05-2005	Hirano, Yuji	424/070.27
*	D	US-2003/0208858	11-2003	Hirano, Yuji	8/406
*	E	US-2003/0215416	11-2003	Hirano, Yuji	424/70.31
*	F	US-2003/0215410	11-2003	Hirano, Yuji	424/70.2
*	G	US-2005/0095212	05-2005	Hirano, Yuji	424/070.11
*	H	US-2004/0115162	06-2004	Hoshino et al.	424/070.31
	T	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.